

Download Noncontact Atomic Force Microscopy

Atomic force microscopy (AFM) or scanning force microscopy (SFM) is a very-high-resolution type of scanning probe microscopy (SPM), with demonstrated resolution on the order of fractions of a nanometer, more than 1000 times better than the optical diffraction limit. Non-contact atomic force microscopy (nc-AFM), also known as dynamic force microscopy (DFM), is a mode of atomic force microscopy, which itself is a type of scanning probe microscopy. Reliable, Dependable, Proven, so you can sleep at night. Choose Kaman and forget about it. NT-MDT Spectrum Instruments develops and supplies unique instrumentation for AFM integration with various optical microscopy and spectroscopy techniques.